



# SiC Megawatt Technology Annual Briefing

**October 17, 2000** 







#### Agenda



- Overview
- Process Development
  - JTE
  - Devices
    - Diodes
    - GTOs
    - JFETs
- Package Development
  - SPCO Package Approach
  - K Technology TPG encapsulated material
- CHPS applications



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## **Megawatt Program Objectives**



- Develop SiC Power GTO, JFETs and pn junction diodes with capability up to 5000V/1000A for use in Utility Power Systems
- Achieve intermediate goals of 1kV/5A devices to support Combat Hybrid Power Systems Flywheel Inverter construction
- •Initiate the development of a packaging approach for a 5kV/200A package

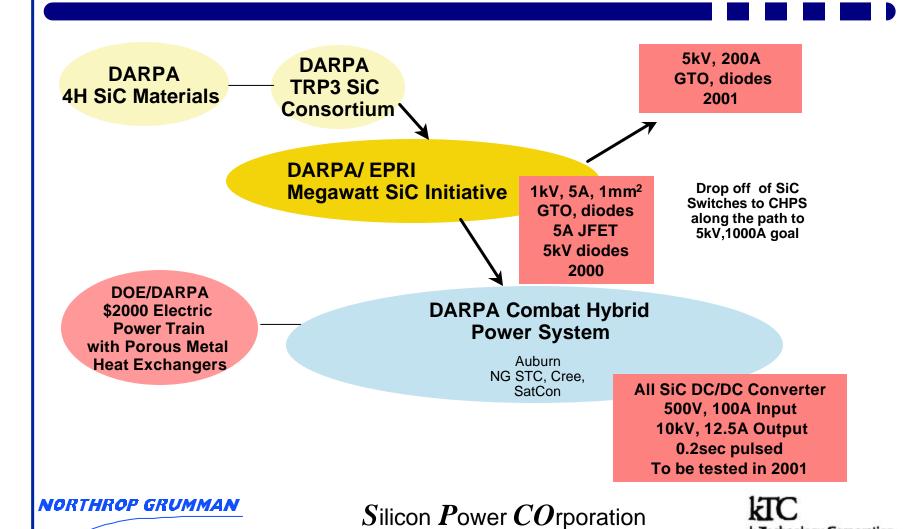


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#### **SiC Evolution**

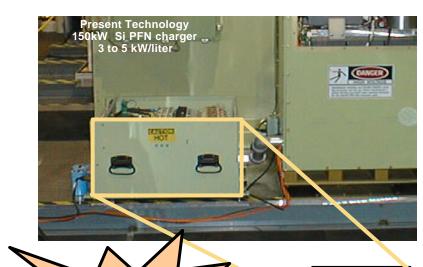




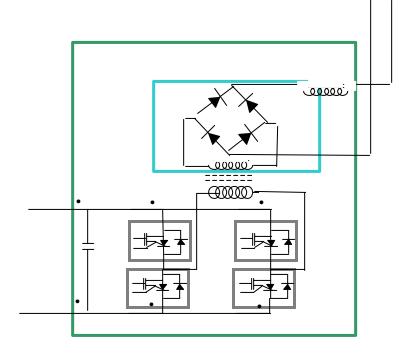


#### SiC DC/DC Converter demonstrates merits | = | = | of higher frequency and temperature









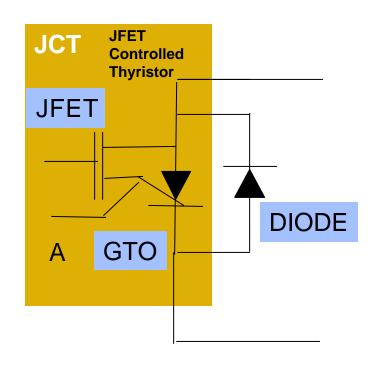
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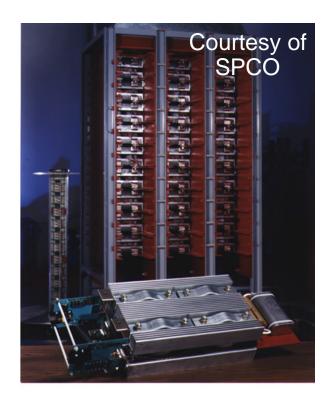




### Building blocks for high power converters FIF and Utility power handling applications







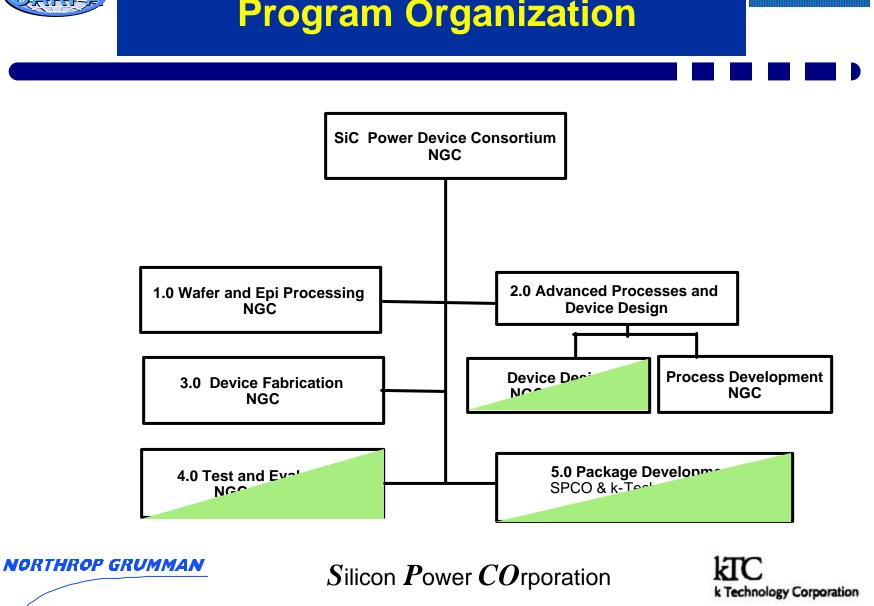
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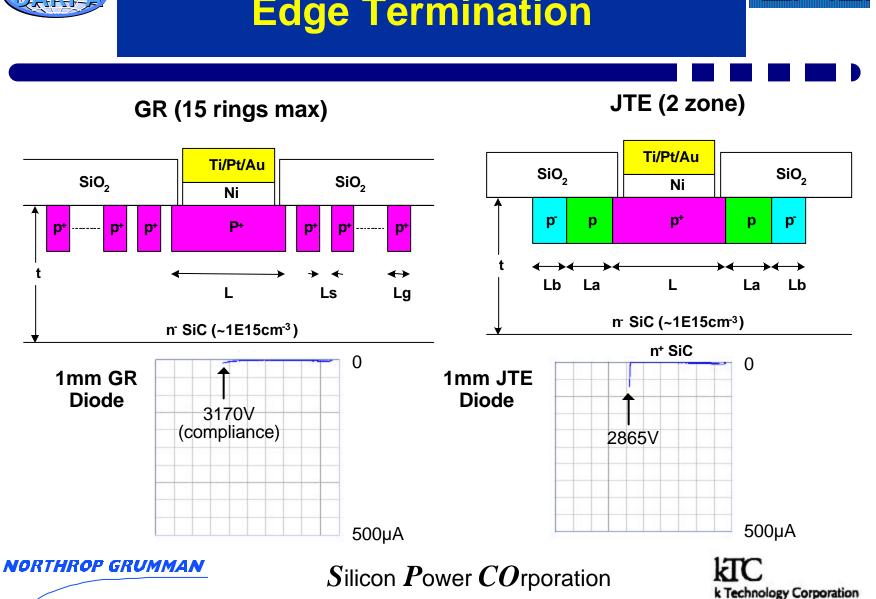








## **Edge Termination**





# High Voltage Diode Edge Termination



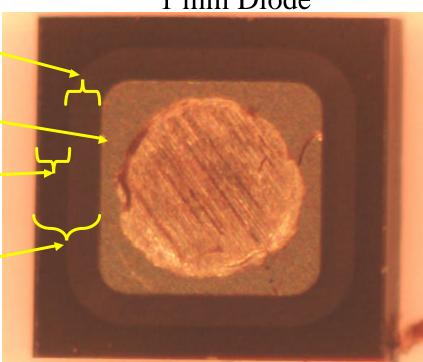
1 mm Diode

Edge Transition

**Bonding Pad** 

Ground

SiO<sub>2</sub>
Dielectric



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# Multizone JTE reduces Surface fields by Order of Magnitude

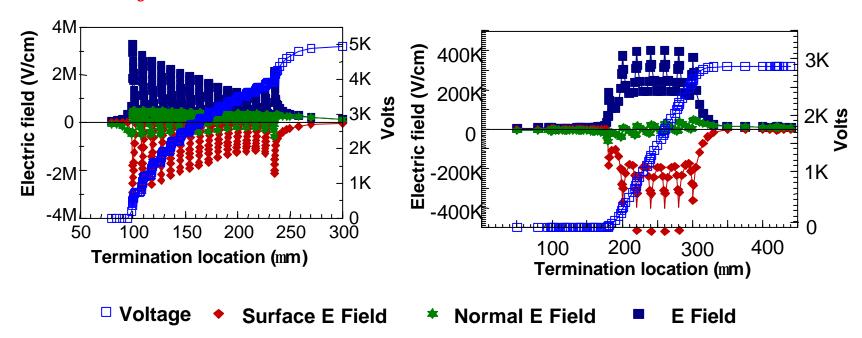


Surface field and voltage for 15 field rings

Surface field and voltage for a 10 zone JTE

Peak surface Field=4E6 V/cm

Peak surface Field = 4E5 V/cm



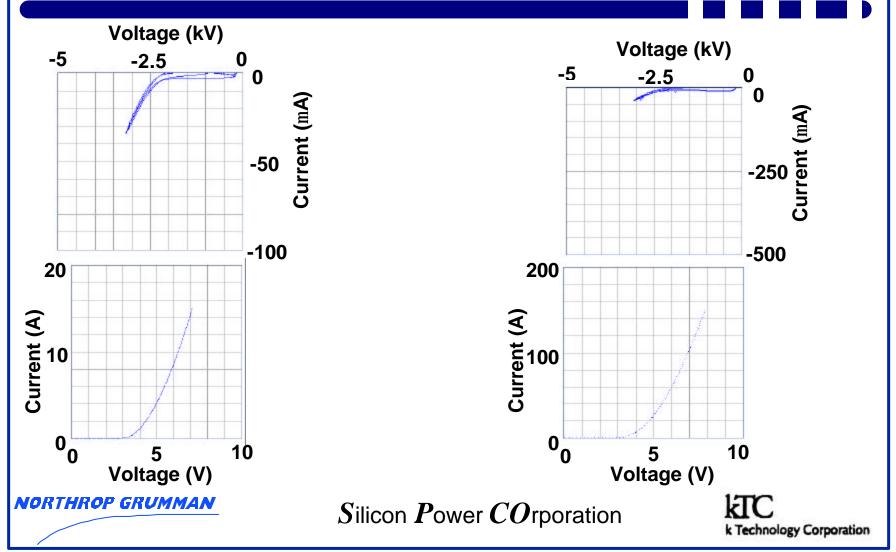
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# Single Diode achieves >3KV and >10A Assembly achieves >3KV & >100A



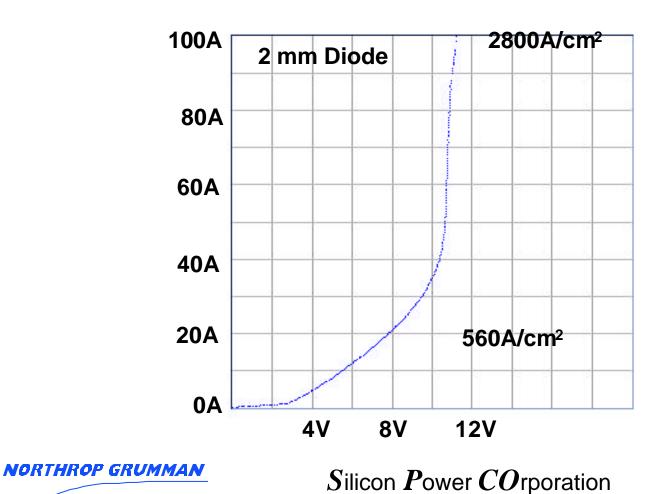






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### SiC is incredibly rugged



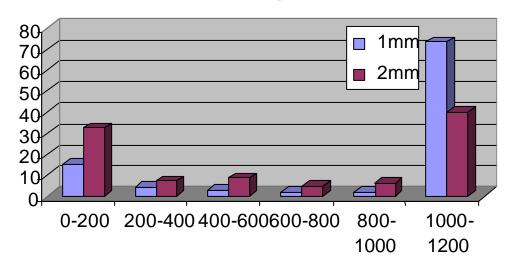
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### Diodes show >70% yield



#### Reverse Voltage @ <50uA



- -Strong dependence on epi quality
- -Reasonable (40%) yields even at 2 mm

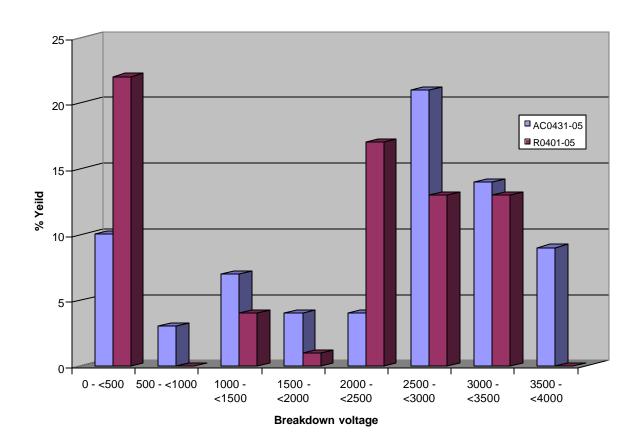
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# **High Voltage Diode Yield**



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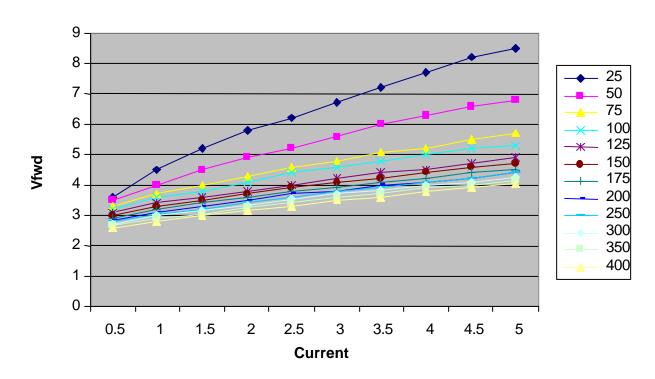




#### Forward drop decreases with temperature



#### Fwd V vs. I as a function of Temperature



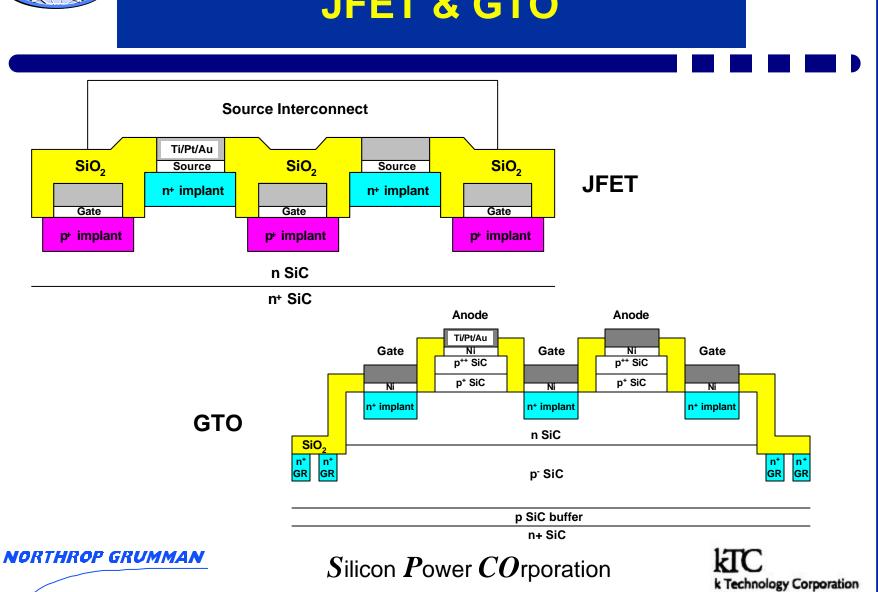
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#### **JFET & GTO**









#### **GTO Device Development**



- GTO anode finger designs:
- •GTO edge terminations: 20 GR 20 zone JTE
- •pnp and npn BJT test structures
- pnpn and npn test diodes with GR and JTE edge terminations
- •PCMs for evaluation of: Electrical properties of top 4 layers Ohmic contacts Electrical activation of implants
- Area for SIMS analysis

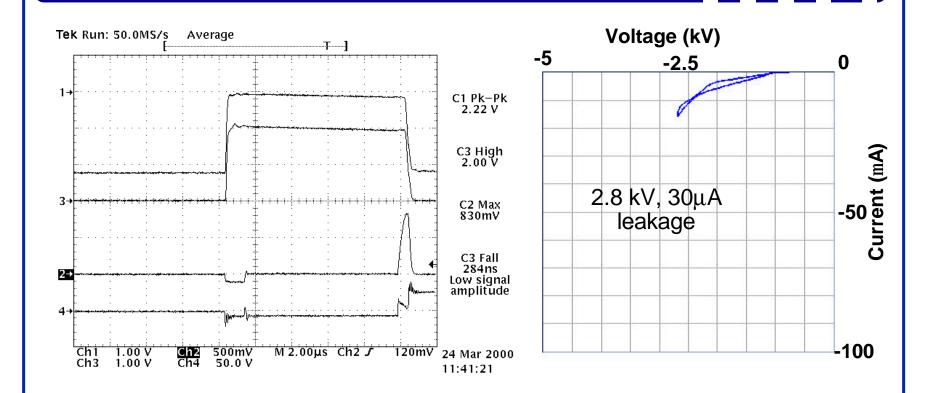
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# 1mm GTO achieves 20A cell 2mm GTO achieves 2.8kV





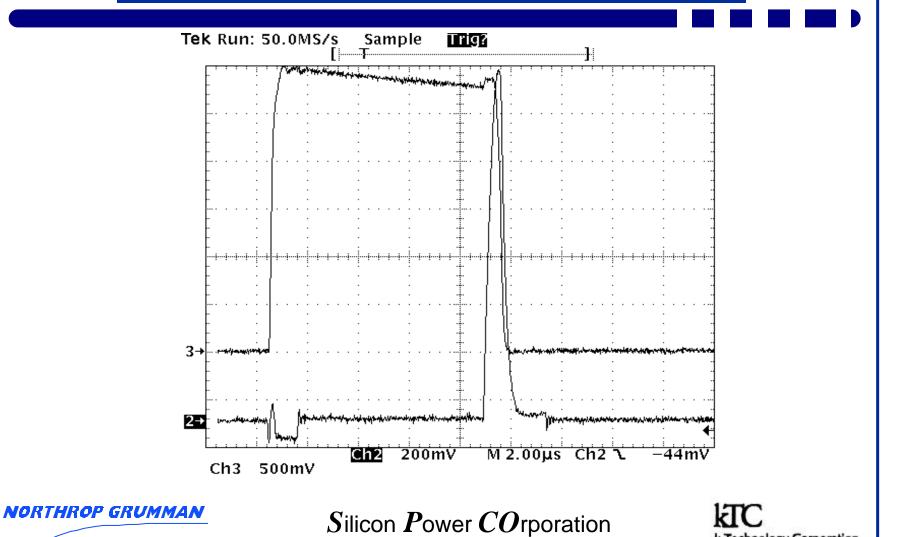
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## 30A assembly





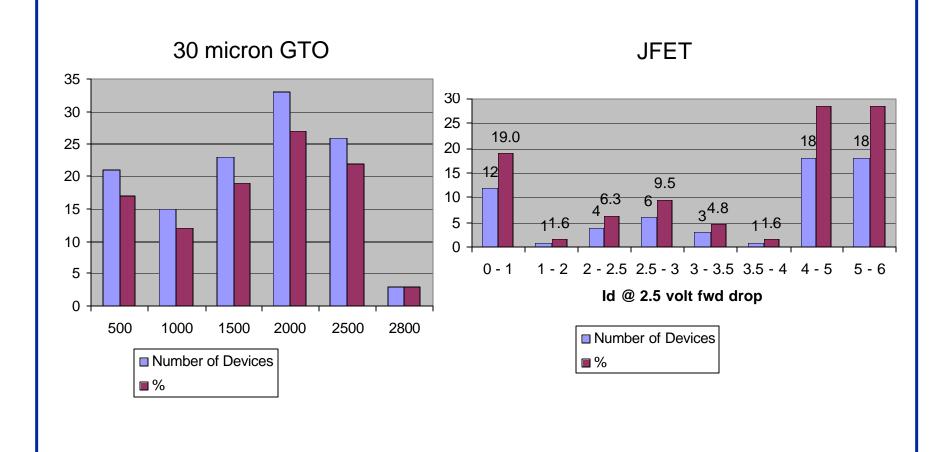


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## GTO Yields ~ 25%@ 2 kV JFET Yields >50% @ 4A



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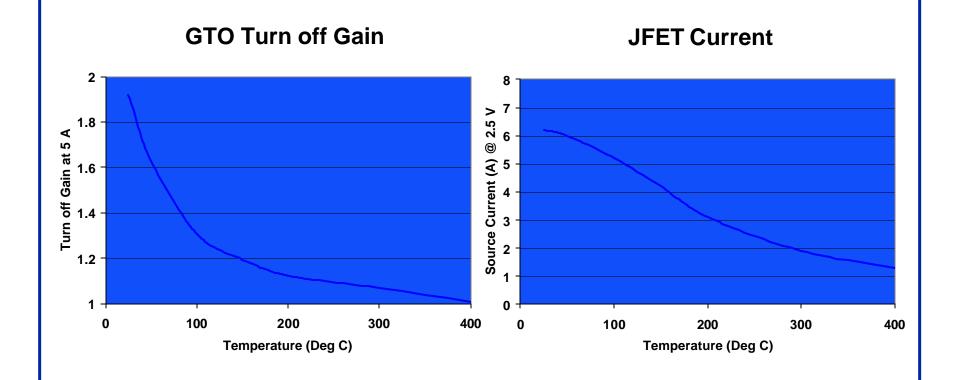


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#### **Turn off Characteristics for JCT**



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# **Device Summary**



Phase I and Phase 2 device goals exceeded

Phase 1

Phase 2

•Diode: 2A cells,30A, 2kV

10 A cell, 100A, 3kV

•GTO: 2A cells, 30A, 2kV

10A cell, 30A, 2.8 kV

•JFET: 1A cells, 5A

2.5A cell, 25A

Demonstrated 30A JCT

•Yields for 1mm above 50%,

•Yields for 2mm are encouraging- >30%

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#### **SPCO** is packaging JCT

#### **Design Specifications**

Current: 200 Amperes

Voltage: 3kV

Temperature range: RT - 250C

- Power density up to 1250 watts/cm²
- Device Specs:
  - RT:
    - GTO 2mm x 2mm/ 20Amp @5 Volts
    - JFET 1mm x 1mm/ 3Amps @ 2 Volts
  - 250C
    - GTO -> 20Amp @5 Volts
    - JFET -1.0Amps @ 2 Volts

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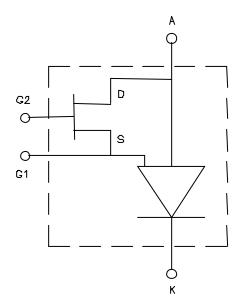






## **JCT Critical Design Issues**

- High GTO power density:
   20A/5V/ Area= .04 cm²/50% Duty
  - 1250 Watts/cm<sup>2</sup>
- High temperature
- Inductance in gate ckt.
- Resistance in gate ckt.
- Height variations from device to device can result in large mechanical stress when paralleled.
- High E-field on top side of GTO cell (3kV across 220 mm gap)





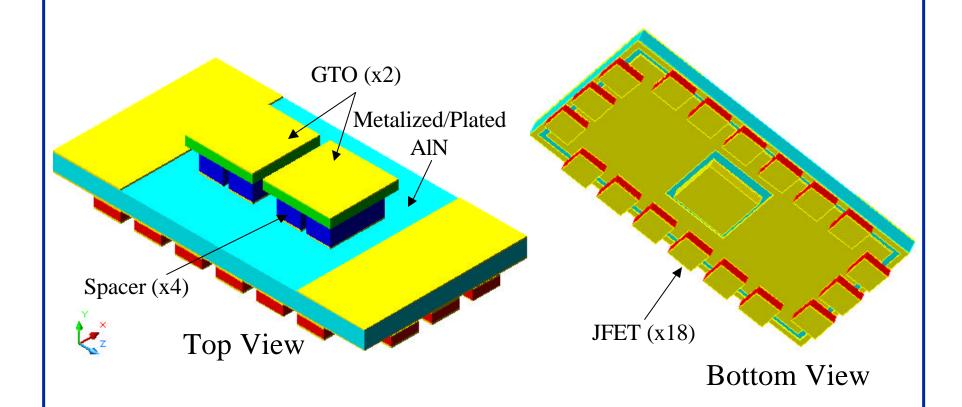
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# **40 Amp JCT Module**



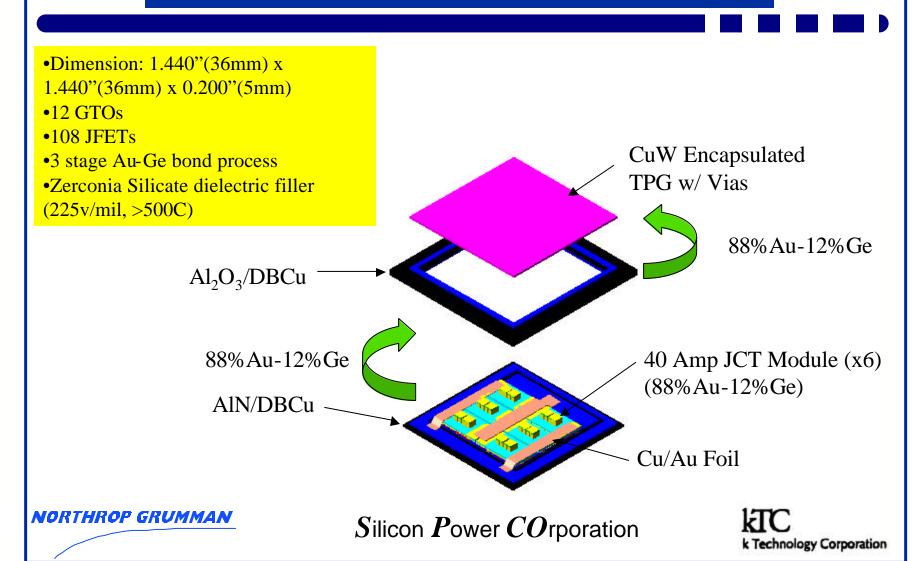
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## 200 Amp Package Design

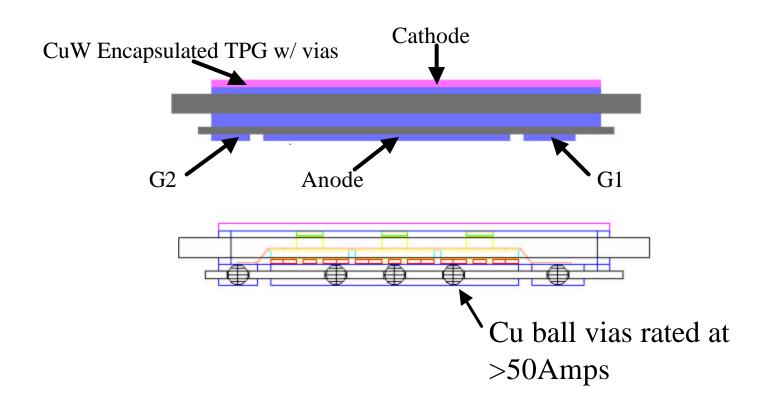




# 200 Amp JCT Package



(Continued)



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#### **TPG** enhances thermal conduction



Thermal Pyrolytic Graphite (TPG) Kxx=Kyy = 1700 W/mK Kzz=10 W/mK Encapsulant

#### Material Concept

- The TPG Insert Provides a High Thermal Conduction Path
- The Encapsulation Material Provides Tailorable CTE Mounting Surface
- There Is Negligible In-plane Structural Coupling Between the TPG and Encapsulant

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TPG Properties Silicon  $m{P}$ ower  $m{CO}$ rporation





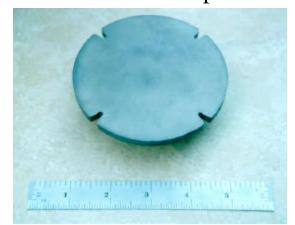
### **TPG Encapsulation Demonstration**



#### **TPG** Insert



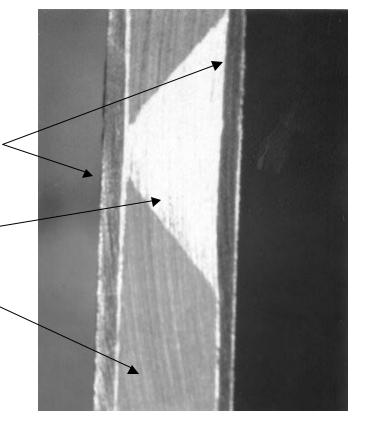
AlSiC/TPG Heat Spreader



AlSiC



**TPG** 



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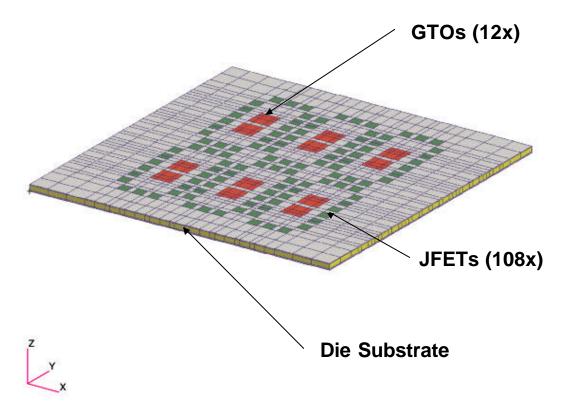
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### **200 Amp Package Thermal Analysis**



- Finite Element Model
  - ABAQUS FiniteElement Code
  - 3D Heat TransferElement
  - 4800 Nodes
  - 3393 Elements
  - Processed on HPC3000 Platform



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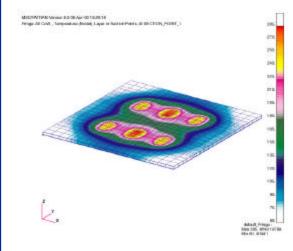


### **Thermal Analysis**



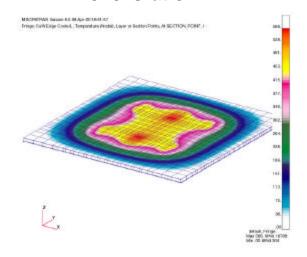
#### Case 1

- Back Surface Convection
- Material CuW
- Thickness 0.6mm
- Maximum Temperatures
  - 285°C at GTO
  - 235°C at JFET



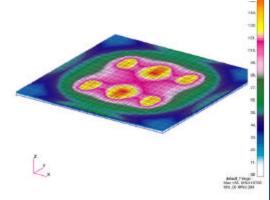
#### Case 2

- Circumferential Cooling
- Material CuW
- Thickness 0.6mm
- Maximum Temperature
  - 566°C at GTO
  - 515°C at JFET



#### Case 3

- Circumferential Cooling
- Material CuW
   Encapsulated TPG
- Thickness 0.6mm
- Maximum Temperature
  - 169°C at GTO
  - 112°C at JFET



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### **Summary**



- Megawatt demonstrates enhanced thermal and electrical properties of SiC
- •As substrates are improved larger devices will be feasible
- Single Devices achieve >500W/cm, >20A, >3kV
- Advanced packaging concepts will integrate a200A package with advanced TPG materials
- •CHPS will provide a near term demonstration



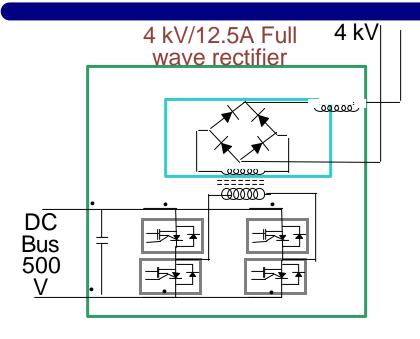




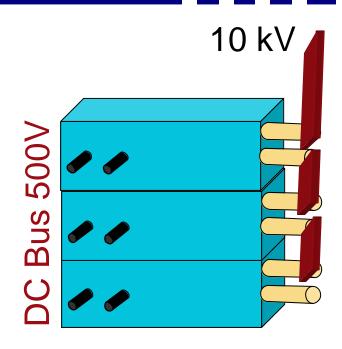
# CHPS Air cooled, upgradable modules deliver 0.2 sec pulse at 150 kW







Module holds 500V/100A H Bridge with four 100A sandwiches 400C junction temp. on switches and 250C on rectifier 100 kHz



Three 50 kW modules in series to achieve 10kV and 150kW for 3 modules in series









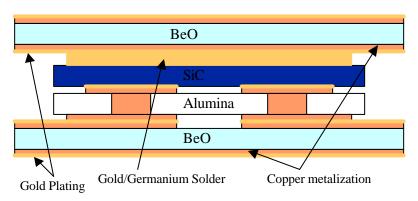


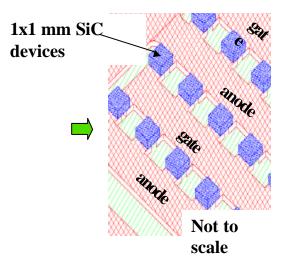


# First samples of Substrates using BeO for both Switch and Rectifier received









#### We have settled on BeO as the substrate material

- AIN process needs more development--- beyond CHPS
- In addition to better yields, this drove the selection of 1x1mm devices.
- Sandwich Implementation indicates basic approach works
  - 100A Switch Design in Progress
  - Alumina Feedthrus production process optimized













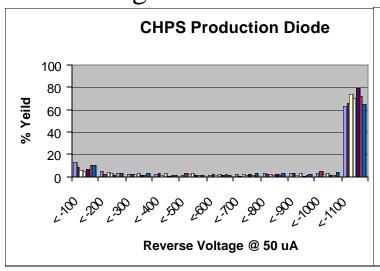
#### **Device Yields have been Good**

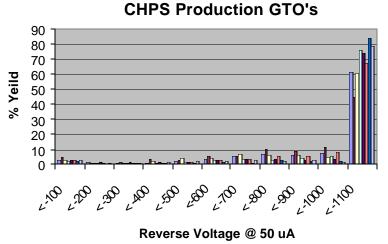




#### Low Voltage Diode Yield - 70%

#### GTO Yield - 53%















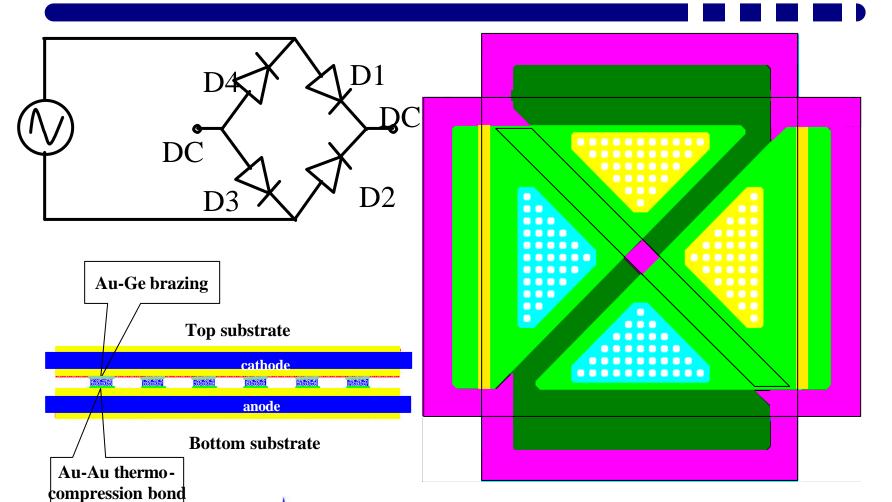


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## Rectifier









A U B U R N ENGINEERING



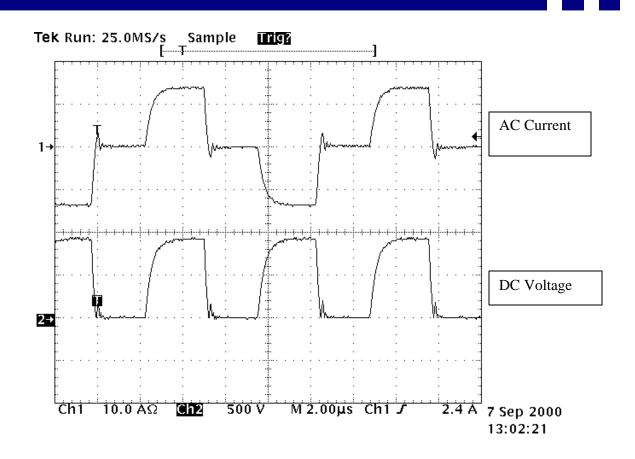




### Rectifier - 14A @ 1kV & 100kHz

















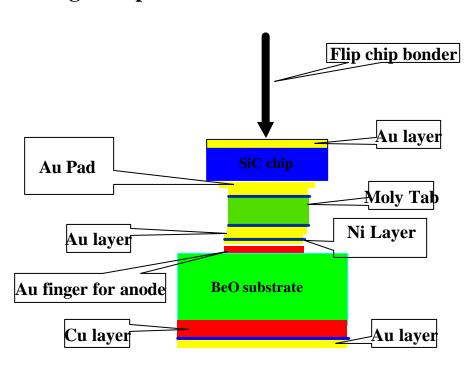


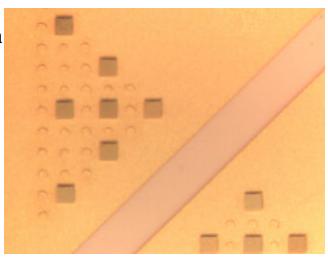
#### **Thermo-compression Bonding of Die**

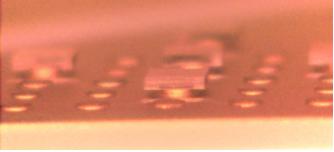




- Process: 380°C for 120 sec at 3-6 kg in air
- High temperature bond: Au-Au solid diffusion



















#### **Switch Sandwich**





#### Switch #1 - 5A at 400V

